Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/785,445	WANG ET AL.
Examiner	Art Unit
Matthew D. Matzek	1771

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SEARCHED					
Class	Subclass	Date	Examiner		
445	82,88,94	11/20/05	мм		
977	016.1	11/20/05	мл		
428	400	11/21/05	им		
search:					
442	221	6/17/06	мм		
	268 286		1		
	315				
	370 381				
	394				
428	174~				
	180~	1	1		

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
E KST	2/1/05	мл		
INVENTOR ASSIGNAC	11/30/.5	איע		
192	12/1/05	мм		